## **CYTOP** pattern processing method

Precautions for handling

Please be sure to read MSDS before using this product to ensure safe handling.

## When applying a micro-pattern on the CYTOP during the LSI drying process, pay attention to the following:

## **1** Example of surface modification conditions for resist application

CYTOP is a perfluoropolymer. The surface is water and oil repellentand a normal photoresist is repelled by CYTOP. It cannot be coated directly. To apply a general resist on CYTOP, it is effective to modify the surface with plasma processing. (Corona discharge is not recommended because wetness is not sufficient.)

Example of equipment conditions: Parallel substrate plasma etcher (cathode couple) Example of distance between substrates: 48 mm

Example of plasma conditions: Pressure 0.6 Torr, Rf power 300 W (0.42 W/cm<sup>2</sup>)

Example of resist: Novolac-based photoresist OFTR-800,60TSMR-8900, 50 cp product (Tokyo Ohka Kogyo Co., Ltd.) [Current the product number is obsolete.]

Test results

Plasma processing conditions	CYTOP film reduction (nm)	Ease of resist application
None	—	Repellence occurs. It is difficult to apply.
N <sub>2</sub> 0.5 min.	30	Good.
$N_2 = 1 \min$ .	60	Good.
Ar 1 min.	15	Good.
O <sub>2</sub> 1 min.	100	Good.

As described above, resist can be applied after processing for a short time with any gas.

## 2 Etching conditions

As shown below, the selection ratio with resist only for  $O_2$  is about 2.

Etching conditions: Parallel substrate (cathode couple), Distance between substrates = 48 mm,  $O_2$  flow rate = 180 sccm, Pressure = 0.6 Torr, Rf power = 300 W (0.42 W/cm<sup>2</sup>)

02 flow fate = 180 secfil, flessure = 0.0 foll, Ki power = 500 w (0.42)





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